

TECHNOMETRICS

Volume 52, Number 3, August 2010

Nonparametric Profile Monitoring by Mixed Effects Modeling Peihua Qiu, Changliang Zou, and Zhaojun Wang	265	Approximate Tolerance Limits Under Log-Location-Scale Regression Models in the Presence of Censoring Takeshi Emura and Hsiuying Wang	313
Comment Daniel W. Apley	277	Bayesian Reliability, Availability, and Maintainability Analysis for Hardware Systems Described Through Continuous Time Markov Chains Javier Cano, Javier M. Moguerza, and David Ríos Insua	324
Comment Hugh A. Chipman, R. Jock MacKay, and Stefan H. Steiner	280	Improving on Estimation for the Generalized Pareto Distribution Jin Zhang	335
Comment F. Tsung	283	Likelihood Analysis of Multivariate Probit Models Using a Parameter Expanded MCEM Algorithm Huiping Xu and Bruce A. Craig	340
Comment William H. Woodall, Jeffrey B. Birch, and Pang Du	285	Some Notes on the Nonnegative Garrote Shifeng Xiong	349
Rejoinder Peihua Qiu, Changliang Zou, and Zhaojun Wang	288	Book Reviews	362
Leveraged Gauge R&R Studies Ryan Browne, Jock MacKay, and Stefan Steiner	294	Announcement of Ziegel Prize	371
One-Sided Tolerance Limits for Balanced and Unbalanced Random Effects Models David Hoffman	303		